Perpendicular Orientation of Microdomains in PS-\textit{b}-PMMA Thin Films on the PS brushed Substrates

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\textbf{Figure S1.} The SFM phase images for lamellar morphology on a PS brushed substrate with $\sigma = 0.116$ chains/nm$^2$, and the corresponding 2D-GISAXS patterns at an incidence angle ($\alpha_i$) of 0.190 $^\circ$, where the film thickness of lamella-forming PS-\textit{b}-PMMA were varied. All the film samples were annealed at 180 $^\circ$C under vacuum for 24 h to obtain an equilibrium morphology.